

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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N-Channel Power MOSFET 600 V, 4.8 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	V _{DSS}	600		٧
Continuous Drain Current $R_{\theta JC}$ (Note 1)	Ι _D	2.4	2.2	Α
Continuous Drain Current $R_{\theta JC}$ $T_A = 100^{\circ}C$ (Note 1)	I _D	1.6	1.4	Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	10	9	Α
Power Dissipation $R_{\theta JC}$	P_{D}	24	57	W
Gate-to-Source Voltage	V _{GS}	±30		V
Single Pulse Avalanche Energy, I _D = 2.4 A	E _{AS}	120		mJ
ESD (HBM) (JESD 22-A114)	V _{esd}	2500		٧
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 17)	V _{ISO}	4500		V
Peak Diode Recovery (Note 2)	dv/dt	4.5		V/ns
Continuous Source Current (Body Diode)	Is	2.4		Α
Maximum Temperature for Soldering Leads	TL	260		°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Limited by maximum junction temperature
- 2. $I_{SD} = 2.4 \text{ A}$, $di/dt \le 100 \text{ A/}\mu\text{s}$, $V_{DD} \le BV_{DSS}$, $T_J = +150^{\circ}\text{C}$



ON Semiconductor®

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V _{DSS}	R _{DS(on)} (MAX) @ 1 A
600 V	4.8 Ω

N-Channel D (2) G (1) S (3)



NDF02N60ZG, NDF02N60ZH TO-220FP CASE 221AH



NDD02N60Z-1G IPAK CASE 369D



NDD02N60ZT4G DPAK CASE 369AA

ORDERING AND MARKING INFORMATION

See detailed ordering, marking and shipping information on page 7 of this data sheet.

THERMAL RESISTANCE

Parameter		Symbol	Value	Unit
Junction-to-Case (Drain)	NDF02N60Z NDD02N60Z	$R_{\theta JC}$	4.9 2.2	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF02N60Z (Note 4) NDD02N60Z (Note 3) NDD02N60Z-1	$R_{ hetaJA}$	51 41 80	

^{3.} Insertion mounted

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise noted)

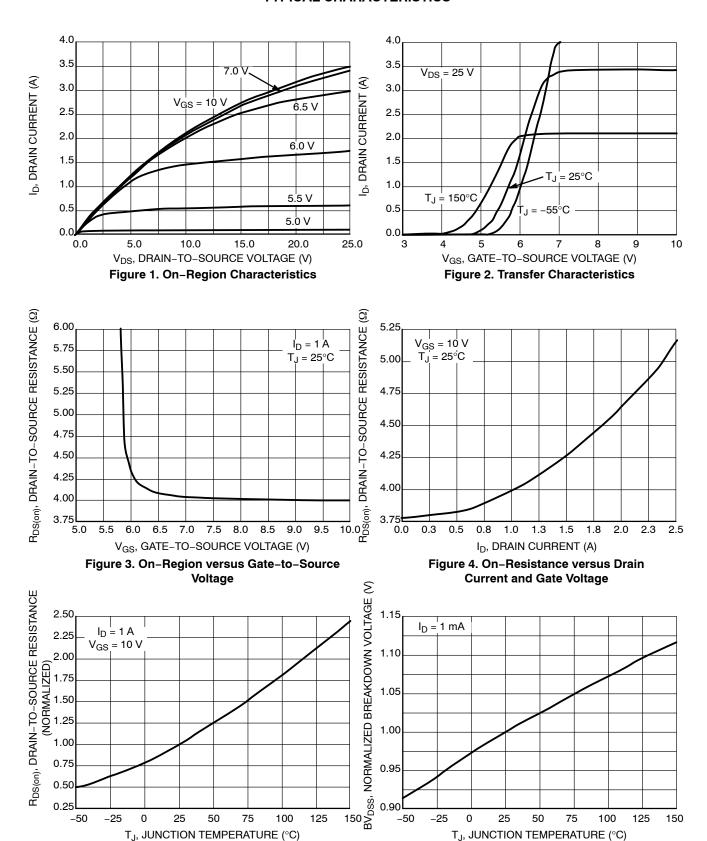
Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	•
Drain-to-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 1 mA		BV _{DSS}	600			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C I _D = 1 mA	> ,	$\Delta BV_{DSS}/\Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	V 000 V V 0 V	25°C	I _{DSS}			1	μΑ
	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	150°C				50	1
Gate-to-Source Forward Leakage	V _{GS} = ±20 V		I _{GSS}			±10	μΑ
ON CHARACTERISTICS (Note 5)					•	•	
Static Drain-to-Source On-Resistance	V _{GS} = 10 V, I _D = 1.0) A	R _{DS(on)}		4.0	4.8	Ω
Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 50	μΑ	V _{GS(th)}	3.0	4.0	4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 1.2 A		9FS		1.7		S
DYNAMIC CHARACTERISTICS							
Input Capacitance (Note 6)	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		C _{iss}	215	274	325	pF
Output Capacitance (Note 6)			C _{oss}	25	34	45	1
Reverse Transfer Capacitance (Note 6)			C _{rss}	4.0	7.0	10	
Total Gate Charge (Note 6)			Qg	5.0	10	16	nC
Gate-to-Source Charge (Note 6)	V _{DD} = 300 V, I _D = 2.4 A,		Q_{gs}	1.5	2.4	4.0	
Gate-to-Drain ("Miller") Charge (Note 6)	V _{GS} = 10 V		Q _{gd}	3.5	5.3	8.0	
Plateau Voltage			V _{GP}		6.4		V
Gate Resistance			R _g		4.9		Ω
RESISTIVE SWITCHING CHARACTERISTI	cs				•	•	•
Turn-On Delay Time			t _{d(on)}		9.0		ns
Rise Time	V_{DD} = 300 V, I_{D} = 2.4 A, V_{GS} = 10 V, R_{G} = 5 Ω		t _r		7.0		
Turn-Off Delay Time			t _{d(off)}		15		
Fall Time			t _f		7.0		
SOURCE-DRAIN DIODE CHARACTERIST	ICS (T _C = 25°C unless other	erwise not	ed)				
Diode Forward Voltage	I _S = 2.4 A, V _{GS} = 0	٧	V_{SD}			1.6	V
Reverse Recovery Time	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_S = 2.4 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		t _{rr}		240		ns
Reverse Recovery Charge			Q _{rr}		0.7		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{4.} Surface mounted on FR4 board using 1" sq. pad size, (Cu area = 1.127 in sq [2 oz] including traces).

^{5.} Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.
6. Guaranteed by design.

TYPICAL CHARACTERISTICS



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Figure 6. BV_{DSS} Variation with Temperature

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS

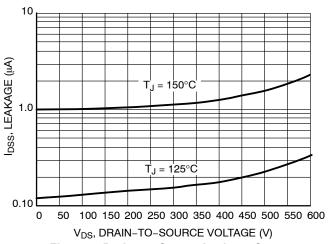


Figure 7. Drain-to-Source Leakage Current versus Voltage

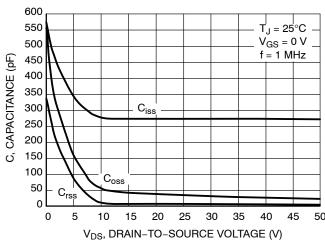


Figure 8. Capacitance Variation

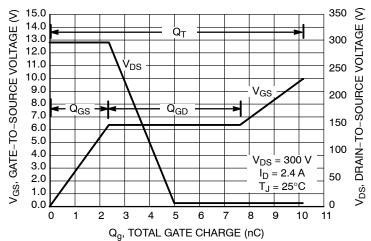


Figure 9. Gate-to-Source Voltage and Drain-to-Source Voltage versus Total Charge

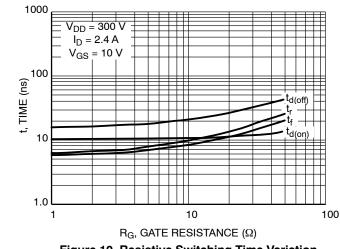


Figure 10. Resistive Switching Time Variation versus Gate Resistance

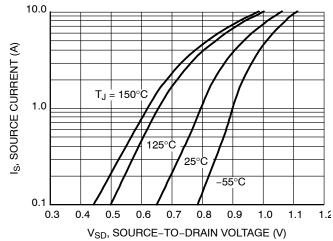


Figure 11. Diode Forward Voltage versus Current

TYPICAL CHARACTERISTICS

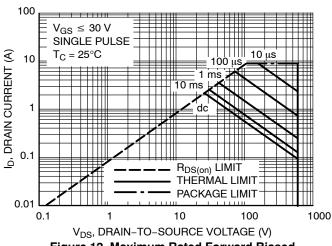


Figure 12. Maximum Rated Forward Biased
Safe Operating Area NDD02N60Z

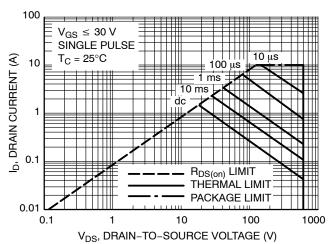


Figure 13. Maximum Rated Forward Biased Safe Operating Area NDF02N60Z

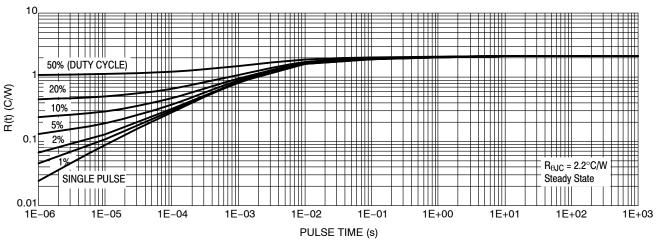


Figure 14. Thermal Impedance (Junction-to-Case) for NDD02N60Z

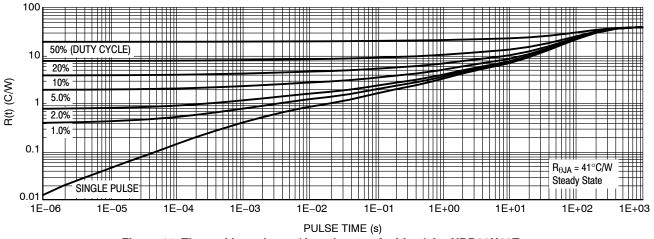


Figure 15. Thermal Impedance (Junction-to-Ambient) for NDD02N60Z

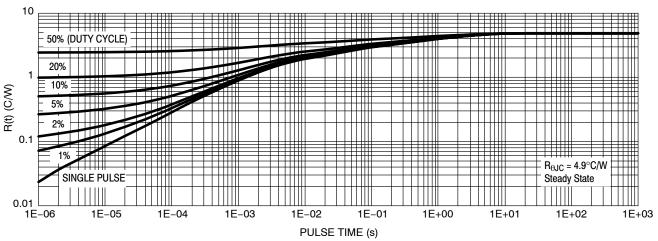


Figure 16. Thermal Impedance (Junction-to-Case) for NDF02N60Z

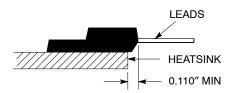


Figure 17. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

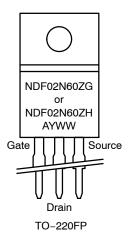
*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

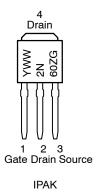
ORDERING INFORMATION

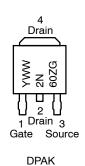
Order Number	Package	Shipping [†]
NDF02N60ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF02N60ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDD02N60Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD02N60ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape and Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MARKING DIAGRAMS







A = Location Code

Y = Year

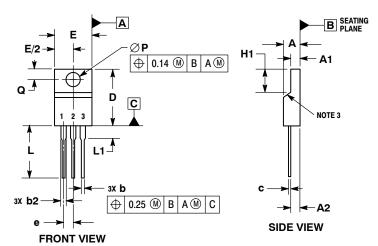
WW = Work Week

G, H = Pb-Free, Halogen-Free Package

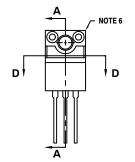
PACKAGE DIMENSIONS

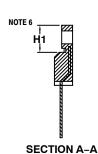
TO-220 FULLPACK, 3-LEAD

CASE 221AH **ISSUE F**









ALTERNATE CONSTRUCTION

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: MILLIMETERS.

 3. CONTOUR UNCONTROLLED IN THIS AREA.

 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY.

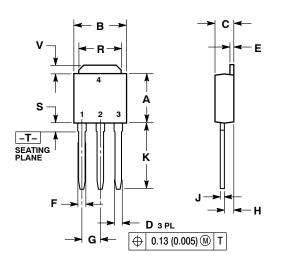
 5. DIMENSION DE DOES NOT INCLUDE DAMBAR PROTRUSION. LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.

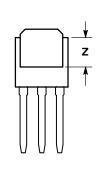
 6. CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY MAY VARY WITHIN THE ENVELOP DEFINED BY DIMENSIONS A1 AND H1 FOR MANUFACTURING PURPOSES.

	MILLIMETERS			
DIM	MIN	MAX		
Α	4.30	4.70		
A1	2.50	2.90		
A2	2.50	2.90		
b	0.54	0.84		
b2	1.10	1.40		
С	0.49	0.79		
D	14.70	15.30		
Ε	9.70	10.30		
е	2.54	BSC		
H1	6.60	7.10		
L	12.50	14.73		
L1		2.80		
P	3.00	3.40		
Q	2.80	3.20		

PACKAGE DIMENSIONS

IPAK CASE 369D ISSUE C





- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

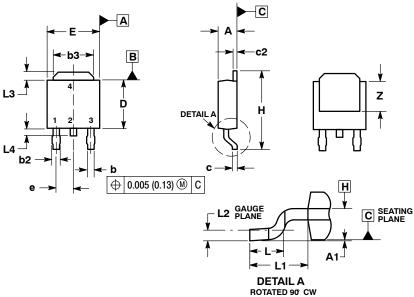
	INCHES		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	
Α	0.235	0.245	5.97	6.35	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.027	0.035	0.69	0.88	
Е	0.018	0.023	0.46	0.58	
F	0.037	0.045	0.94	1.14	
G	0.090	0.090 BSC		BSC	
Н	0.034	0.040	0.87	1.01	
J	0.018	0.023	0.46	0.58	
K	0.350	0.380	8.89	9.65	
R	0.180	0.215	4.45	5.45	
s	0.025	0.040	0.63	1.01	
٧	0.035	0.050	0.89	1.27	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE)

CASE 369AA **ISSUE B**



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
 2. CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE.
 DIMENSIONS D AND E ARE DETERMINED AT THE
 OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PI ANF H

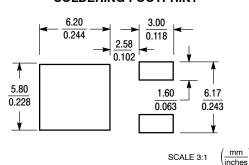
	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
O	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090 BSC		2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74 REF		
L2	0.020	BSC	0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE

2. DRAIN 3. SOURCE

DRAIN

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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